

**Notice of References Cited**

Application/Control No.

09/372,879

Applicant(s)/Patent Under  
Reexamination  
SIDIROPOULOS ET AL.

Examiner

Dana Farahani

Art Unit

2814

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	E	US-			
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	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP-60000769-A	01-1985	JPO	SAKAI et al.	
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	P					
	Q					
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	U	Adel S. Sedra and Kenneth C. Smith, Microelectronic Circuits 1998, Oxford University Press, 4 <sup>th</sup> Edition, PP. 358-359
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